Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,259	OHKAWA ET AL.	
Examiner	Art Unit	
B. Chen	1762	

SEARCHED			
Class	Subclass	Date	Examiner
427	255.29 255.31	6/21/2005	вс
	376.2		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	1		

(INCLUDIN	EARCH NOT IG SEARCH	STRATEGY)
		DATE	EXMR
west		6/21/2005	ВС
			